


<b>Search Notes</b> 	<b>Application/Control No.</b> 10669259	<b>Applicant(s)/Patent Under Reexamination</b> TAKAHASHI ET AL.
	<b>Examiner</b> Hung, Yubin	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	166,233,248,250	8/10/07	YH
3458	395.1,403.1	8/10/07	YH
375	240.18,240.19,240.2	8/10/07	YH
708	203	8/10/07	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	8/10/07	YH
ACM	3/20/07	YH
SPIE	3/20/07	YH
IEEE Xplore	3/20/07	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	166, 233, 248	8/10/07	YH
375	240.19	8/10/07	YH
708	203	8/10/07	YH